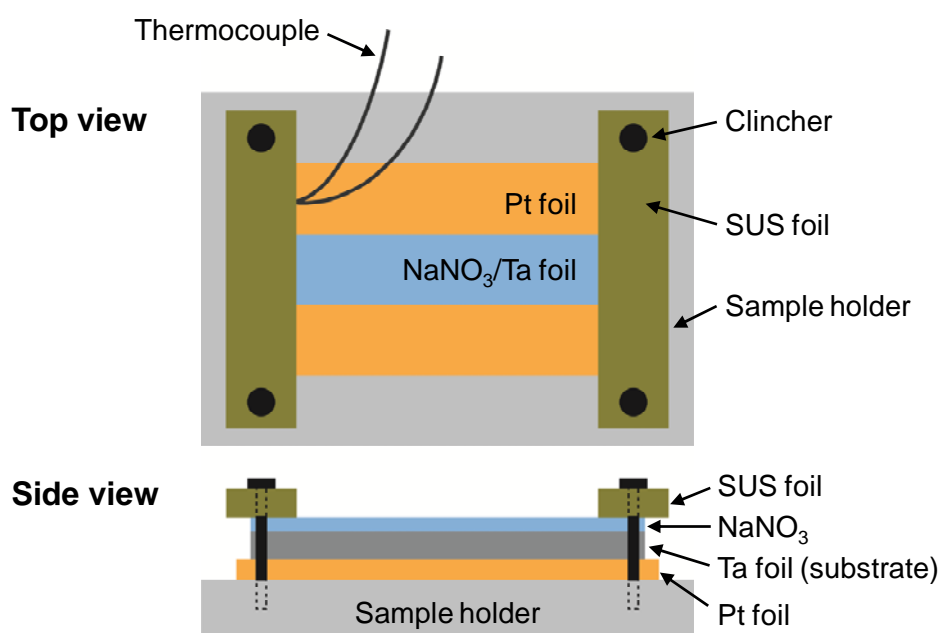
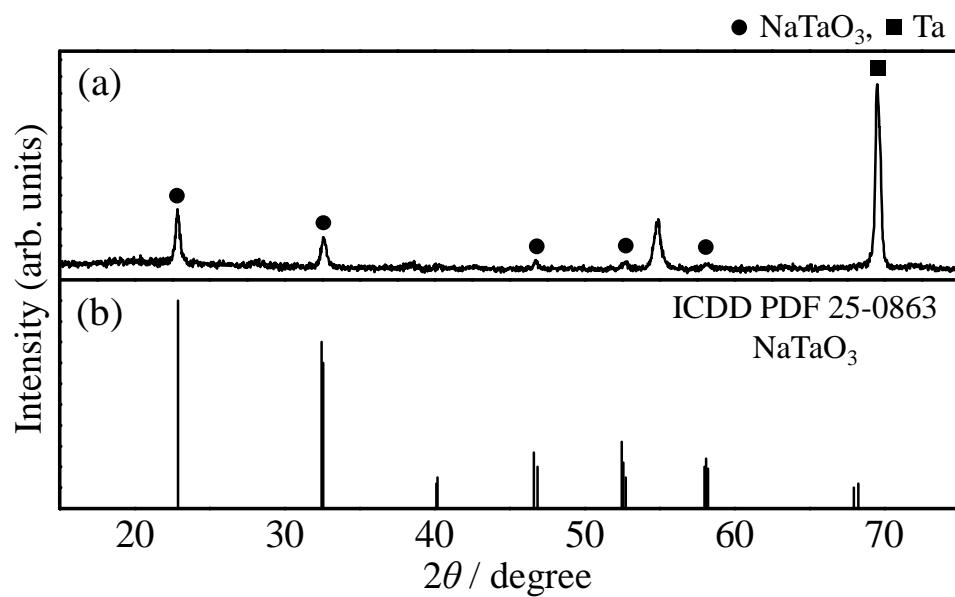


Electronic supplementary information



5

ESI 1 Schematic illustration of NaNO₃-coated Ta substrate on sample holder used for *in-situ* LM observation.



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ESI 2 XRD profiles for (a) crystals grown on Ta substrate during *in-situ* LM observation and for (b) NaTaO₃ ICDD PDF. Diffraction line at $2\theta = 55.6^\circ$ seems to be assigned to Ta-O system, as shown in previous report.¹⁸